# Abstracts

## Robust, model-independent generation of intrinsic characteristics and multi-bias parameter extraction for MESFETs/HEMTs

*A. Ghazinour and R.H. Jansen. "Robust, model-independent generation of intrinsic characteristics and multi-bias parameter extraction for MESFETs/HEMTs." 1998 MTT-S International Microwave Symposium Digest 98.1 (1998 Vol. I [MWSYM]): 149-152.*

This paper presents an improved, model-independent and particularly robust RF characterization and parameter extraction approach based on multi-bias S-parameters. With a new hybrid evolutionary/conjugate gradient strategy, consistent and largely start value-independent results are obtained. Devices from various MMIC foundries are used to demonstrate the quality of this approach.

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